

INTERNATIONAL ELECTROTECHNICAL COMMISSION
COMMISSION ÉLECTROTECHNIQUE INTERNATIONALE

IEC 60384-24
Edition 2.0 2015-07

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**FIXED CAPACITORS FOR USE IN ELECTRONIC
EQUIPMENT**

**CONDENSATEURS FIXES UTILISÉS DANS LES
EQUIPEMENTS ELECTRONIQUES**

**Part 24: Sectional specification – Fixed tantalum
electrolytic surface mount capacitors with
conductive polymer solid electrolyte**

**Partie 24: Spécification intermédiaire –
Condensateurs fixes électrolytiques au tantale
pour montage en surface à électrolyte solide en
polymère conducteur**

CORRIGENDUM 1

Corrections to the French version appear after the English text.

Les corrections à la version française sont données après le texte anglais.

Table 3 – Sampling plan for qualification approval, assessment level EZ

Replace with the following new Table 3:

Group no.	Test	Subclause	Number of specimens n^d	Permissible number of non- conforming items c
0	High surge current ^c	4.18	120+12 ^f	0
	Visual examination	4.4		
	Dimensions	4.4		
	Leakage current	4.5.1		
	Capacitance	4.5.2		
	Tangent of loss angle	4.5.3		
	Equivalent series resistance ^c	4.5.4		
	Spare specimens			
	1A Resistance to soldering heat	4.6	12	0
	Component solvent resistance ^c	4.16		
1B	Solderability	4.7	12	0
	Solvent resistance of marking ^c	4.17		
2	Substrate bending test ^e	4.9	12	0
3 ^a	Mounting	4.3	84	0 ^b
	Visual examination	4.4.2		

		Leakage current	4.5.1			
		Capacitance	4.5.2			
		Tangent of loss angle	4.5.3			
		Equivalent series resistance ^c	4.5.4			
	3.1	Shear test	4.8		12	0
		Rapid change of temperature	4.10			
		Climatic sequence	4.11			
	3.2	Damp heat, steady state	4.12		12	0
	3.3	Characteristics at high and low temperature	4.13		12	0
		Surge voltage	4.14			
	3.4	Endurance	4.15		36	0
	3.5	Storage at high temperature	4.19		12	0
^a The values of these inspections serve as initial inspections for the tests of Group 3. ^b The capacitors found non-conforming after mounting shall not be taken into account when calculating the non-conforming items for the following tests. They shall be replaced by spare capacitors. ^c If required. ^d For case size/voltage combinations, see 3.4.2. ^e Not applicable to capacitors, which shall be mounted on alumina substrates only, according to their detail specification. ^f Spare specimens.						

Table 4 – Test schedule for qualification approval

Replace the row concerning GROUP 3 with the following new row:

GROUP 3	D		See Table 3	
4.3 Mounting		See 4.3.3		
4.3.2 Initial inspections				
Capacitance		See 4.5.2.2		
4.3.4 Final inspections				
Visual examination		See 4.4.2		No visible damage
Leakage current		See 4.5.1.2		See detail specification
Capacitance		See 4.5.2.2		$ \Delta C/C < 8\%$ of value measured in 4.3.2
Tangent of loss angle		See 4.5.3.2		See detail specification
Equivalent series resistance ^e		See 4.5.4.2		See detail specification

4.3 Mounting

Replace with this new subclause 4.3:

4.3 Mounting

4.3.1 General

See IEC 60384-1:2008, 4.33, with the details in 4.3.2, 4.3.3 and 4.3.4.